Search Notes



| Application/Control No. | Applicant(s)/Patent Under Reexamination |
|-------------------------|-----------------------------------------|
| 10620376 | HAYASHI ET AL. |
| Examiner | Art Unit |
| Hodge, Robert | 1795 |

| SEARCHED | | | | | |
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| Class | Subclass | Date | Examiner | | |

| SEARCH NOTES | | | | |
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| Search Notes | Date | Examiner | | |
| Consulted Jonathan Crepeau Re Previous Grounds of Rejection and New Grounds of Rejection and Motivation | 10/24/07 | RWH | | |
| See attached East Search History | 10/24/07 | RWH | | |

| INTERFERENCE SEARCH | | | | | |
|---------------------|----------|------|----------|--|--|
| Class | Subclass | Date | Examiner | | |
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